

About Nano-Reliability

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Abstract

The paper is aimed to identify the main issues linked to the nano-reliability (reliability at nano level) and to propose ways for solving this issues in order to achieve a reliable product. Because nano-technology is a new domain, first, the main concepts and technical terms will be introduced. Than, the main issues of the reliability of nano-structured materials will be described. Eventually, the failure physics for nanodevices will be introduced.

References:

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